


<b>Search Notes</b> 	<b>Application/Control No.</b> 10675529	<b>Applicant(s)/Patent Under Reexamination</b> HEIN, JERRELL
	<b>Examiner</b> Franklin, Richard	<b>Art Unit</b> 2181

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Updated EAST Search	1/19/07	RBF
326/51; 327/291,298; 331/1r,18,107r,108c,108r,158,177r,182,183; 710/1,8,14; 713/600,601; 716/12,16,17; 726/34-36 (Limited EAST Text Search)	1/19/07	RBF
David Martinez (Patent Examiner; Art Unit 2181; 710/1-74)	1/11/07	RBF
Niketa Patel (Patent Examiner; Art Unit 2181; 710/1-74)	1/11/07	RBF
Josh Schneider (Patent Examiner; Art Unit 2182; 710/1-74)	1/11/07	RBF
PLUS 2.0 Search	1/18/07	RBF
Inventor Name Search	1/18/07	RBF
Alan Chen (Patent Examiner; AU 2182; 710/1-74)	1/19/07	RBF

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner